

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/771,542	OKANO, HIDEO	
	Examiner	Art Unit	Page 1 of 1
	Jakieda R Jackson	2655	

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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U	IEEE, The Authoritative Dictionary of IEEE Standards Terms 2000, IEE, 7 th edition	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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